

RoHS Compliant Product
A suffix of "-C" specifies halogen free

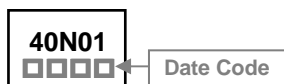
DESCRIPTION

The SSU40n01 is the highest performance trench N-ch MOSFETs with extreme high cell density, which provide excellent $R_{DS(ON)}$ and gate charge for most of the synchronous buck converter applications.

FEATURES

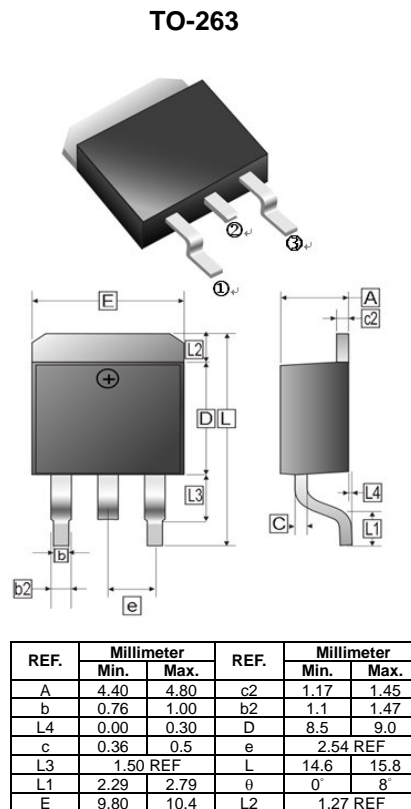
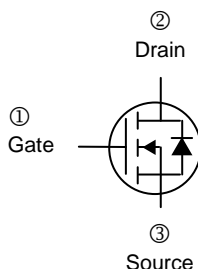
- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS and 100% Rg Guaranteed
- Green Device Available

MARKING



PACKAGE INFORMATION

Package	MPQ	Leader Size
TO-263	0.8K	13 inch



ABSOLUTE MAXIMUM RATINGS ($T_A=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	40	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ¹	I_D	$T_C=25^\circ\text{C}$	149
		$T_C=70^\circ\text{C}$	119
		$T_A=25^\circ\text{C}$	30
		$T_A=70^\circ\text{C}$	24
Pulsed Drain Current ¹	I_{DM}	480	A
Total Power Dissipation	P_D	$T_C=25^\circ\text{C}$	83
		$T_A=25^\circ\text{C}$	2
Single Pulse Avalanche Energy, $L=0.1\text{mH}$	E_{AS}	201	mJ
Single Pulse Avalanche Current, $L=0.1\text{mH}$	I_{AS}	63.5	A
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55~150	$^\circ\text{C}$
Thermal Resistance Rating			
Maximum Thermal Resistance Junction-Ambient ²	$R_{\theta JA}$	62	$^\circ\text{C} / \text{W}$
Maximum Thermal Resistance Junction-Case ²	$R_{\theta JC}$	1.5	$^\circ\text{C} / \text{W}$

ELECTRICAL CHARACTERISTICS ($T_J=25^\circ C$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Static						
Drain-Source Breakdown Voltage	BV_{DSS}	40	-	-	V	$V_{GS}=0, I_D=250\mu A$
Gate-Threshold Voltage	$V_{GS(th)}$	2	3	4	V	$V_{DS}=V_{GS}, I_D=250\mu A$
Gate-Source Leakage Current	I_{GSS}	-	-	± 100	nA	$V_{GS} = \pm 20V$
Drain-Source Leakage Current	I_{DSS}	-	-	1	μA	$V_{DS}=32V, V_{GS}=0$
Static Drain-Source On-Resistance ²	$R_{DS(ON)}$	-	1.9	2.2	m Ω	$V_{GS}=10V, I_D=30A$
Total Gate Charge	Q_g	-	78.8	-	nC	$I_D=30A$ $V_{DS}=20V$ $V_{GS}=10V$
Gate-Source Charge	Q_{gs}	-	23	-		
Gate-Drain ("Miller") Charge	Q_{gd}	-	4.85	-		
Turn-on Delay Time	$T_{d(on)}$	-	21	-	nS	$V_{DS}=20V$ $I_D=30A$ $V_{GS}=10V$ $R_G=3\Omega$
Rise Time	T_r	-	6	-		
Turn-off Delay Time	$T_{d(off)}$	-	98	-		
Fall Time	T_f	-	17	-		
Input Capacitance	C_{iss}	-	4222	-	pF	$V_{GS}=0$ $V_{DS}=20V$ $f=1.0MHz$
Output Capacitance	C_{oss}	-	889	-		
Reverse Transfer Capacitance	C_{rss}	-	398	-		
Guaranteed Avalanche Characteristics						
Single Pulse Avalanche Energy ³	EAS	110	-	-	mJ	$V_{DD}=20V, L=0.1mH, I_{AS}=47A$
Source-Drain Diode						
Diode Forward Voltage	V_{SD}	-	-	1.3	V	$I_S=30A, V_{GS}=0$
Reverse Recovery Time	T_{rr}	-	32	-	ns	$I_F=30A, T_J = 25^\circ C$
Reverse Recovery Charge	Q_{rr}	-	120	-	nC	$di/dt=100A/\mu s$

Notes:

1. The data tested by pulsed, pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.
2. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design. $R_{\theta JA}$ shown below for single device operation on FR-4 in still air.
3. The Min. value is 100% EAS tested guarantee

CHARACTERISTIC CURVES

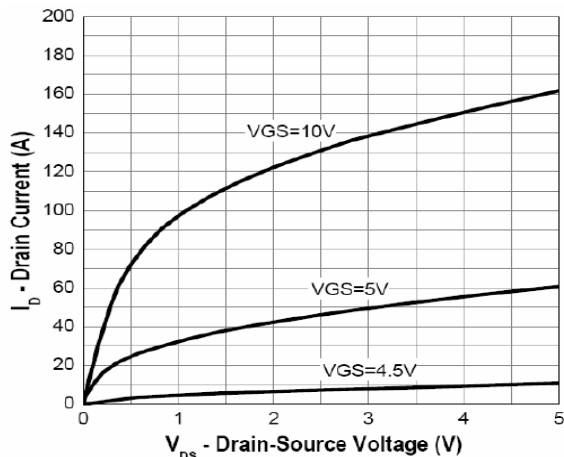


Fig.1 Typical Output Characteristics

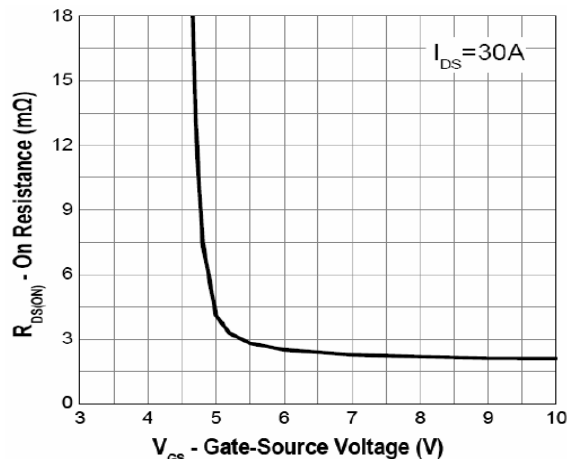


Fig.2 On-Resistance vs. G-S Voltage

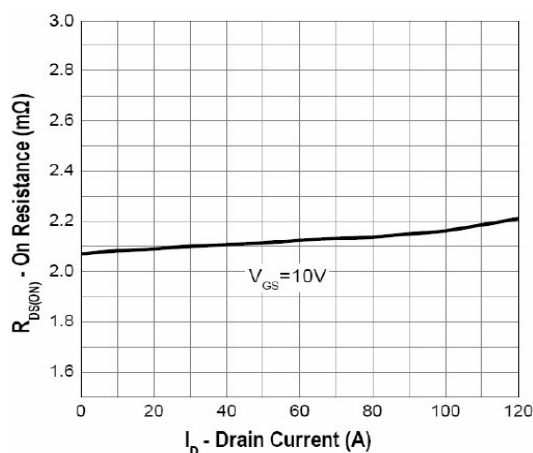


Fig.3 On-Resistance vs. Drain Current

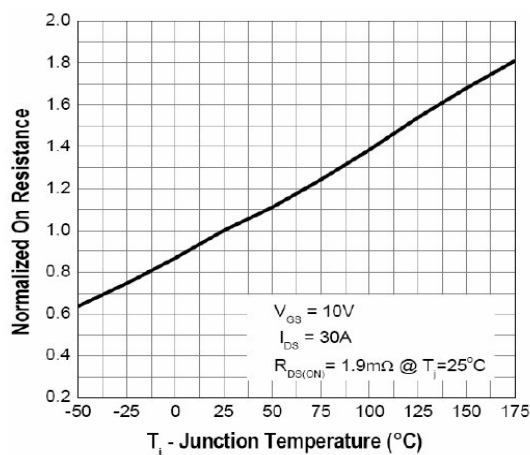


Fig.4 Normalized $R_{DS(ON)}$ vs. T_J

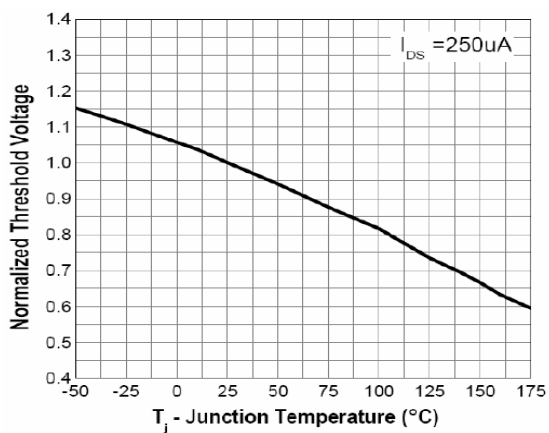


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

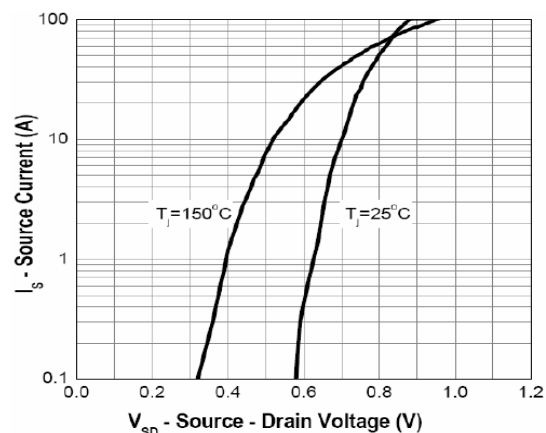


Fig.6 Forward Characteristics of Reverse

CHARACTERISTIC CURVES

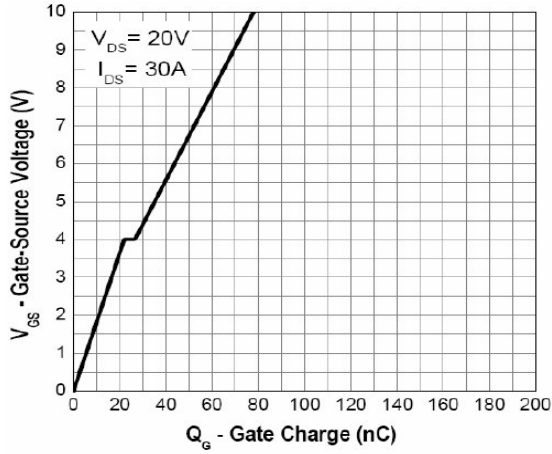


Fig.7 Gate Charge Characteristics

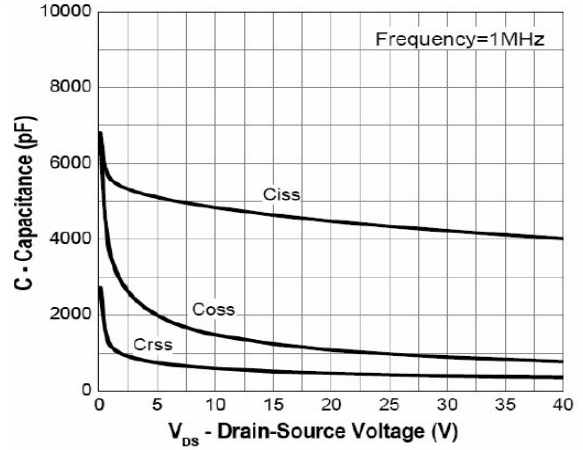


Fig.8 Capacitance Characteristic

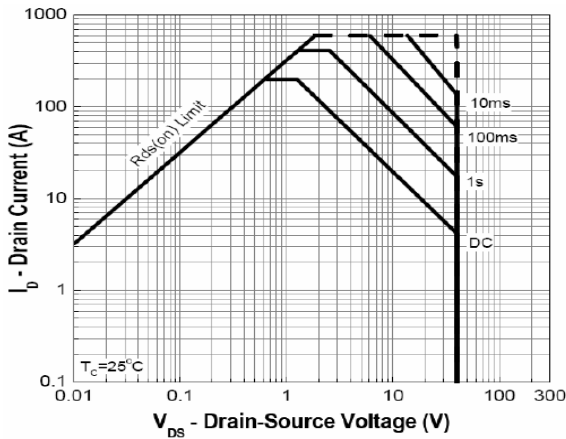


Fig.9 Safe Operating Area

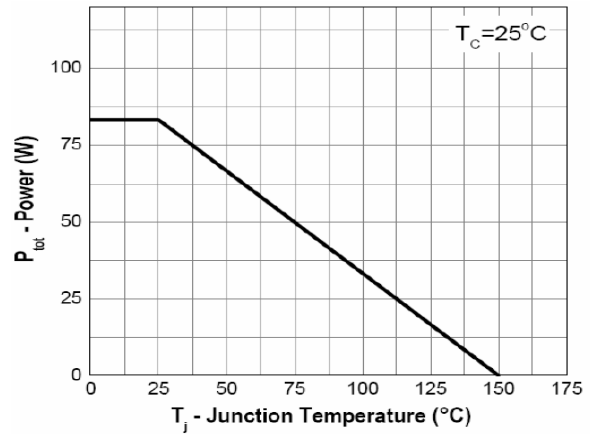


Fig.10 Power Dissipation

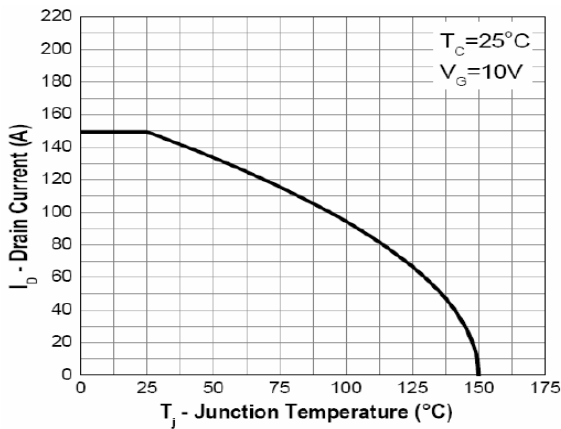


Fig.11 Drain Current vs. T_J

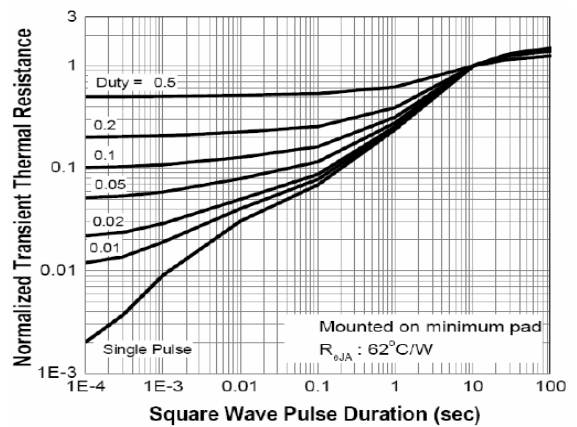


Fig.12 Transient Thermal Impedance